



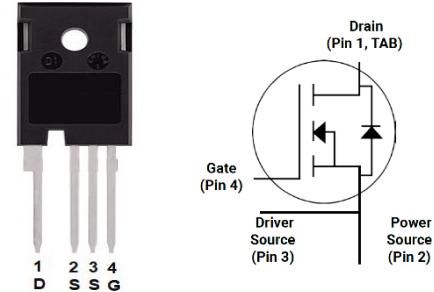
## Features

- High Blocking Voltage
- High Frequency Operation
- Low on-resistance
- Fast intrinsic diode with low reverse recovery

$V_{DS} = 650 \text{ V}$   
 $I_D@25^\circ\text{C} = 92\text{A}$   
 $R_{DS(\text{ON})} = 28\text{m}\Omega$

## Benefits

- Higher System Efficiency
- Parallel Device Convenience without thermal runaway
- High Temperature Application
- Hard Switching & Higher Reliability
- 



## Applications

- Motor Drives
- Solar / Wind Inverters
- Onboard EV Charger
- Energy Storage
- Server
- Telecom
- SMPS
- Uninterruptable power supplies

**TO-247-4**  
**Pin definition**

Part Number	Package	Marking
LGE3M30065Q	TO-247-4	LGE3M30065Q

## Maximum Ratings ( $T_c=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test conditions	Value	Unit
Drain - Source Voltage	$V_{DS\text{max}}$	$V_{GS}=0\text{V}, I_D=100\mu\text{A}$	650	V
Gate - Source Voltage (dynamic)	$V_{GS\text{max}}$	AC ( $f>1 \text{ Hz}$ )	-8 / +23	V
Gate - Source Voltage (static)	$V_{GS\text{op}}$	static	-4 / +18	V
Continuous Drain Current	$I_D$	$V_{GS} = 18\text{V}, T_c=25^\circ\text{C}$ $V_{GS} = 18\text{V}, T_c=100^\circ\text{C}$	92 65	A
Pulsed Drain Current	$I_{D(\text{pulse})}$	$T_c=25^\circ\text{C}$	210	A
Short Circuit Capability	$t_{sc}$	$V_{DD}=400\text{V}, V_{GS}=18\text{V}$	9	$\mu\text{S}$
Short Circuit Capability	$I_{DS}$	$V_{DD}=400\text{V}, V_{GS}=18\text{V}$	400	A
Total power dissipation	$P_D$	$T_c=25^\circ\text{C}$	326	W
Operating Junction Temperature	$T_J$		-55 to 175	$^\circ\text{C}$
Storage Temperature	$T_{STG}$		-55 to 175	$^\circ\text{C}$

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device

Caution: This device is sensitive to electrostatic discharge .Users should follow ESD handing procedures.



**Electrical Characteristics** ( $T_C=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 100\mu\text{A}$	650			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 10\text{mA}$	2.0	2.7	4.0	V
		$V_{DS} = V_{GS}, I_D = 10\text{mA}, T_J = 150^\circ\text{C}$		2.0		V
		$V_{DS} = V_{GS}, I_D = 10\text{mA}, T_J = 175^\circ\text{C}$		1.9		V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 650\text{V}, V_{GS} = 0V$	0	1	100	$\mu\text{A}$
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS} = 18\text{V}, V_{DS} = 0\text{V}$	0	10	200	nA
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS} = -4\text{V}, V_{DS} = 0\text{V}$	-200	-10	0	nA
Drain-Source On-State Resistance	$R_{DS(\text{on})}$	$V_{GS} = 15\text{V}, I_D = 40\text{ A}$		39		$\text{m}\Omega$
		$V_{GS} = 15\text{V}, I_D = 40\text{ A}, T_J = 150^\circ\text{C}$		36		
		$V_{GS} = 15\text{V}, I_D = 40\text{ A}, T_J = 175^\circ\text{C}$		39		
		$V_{GS} = 18\text{V}, I_D = 40\text{ A}$		28	36	
		$V_{GS} = 18\text{V}, I_D = 40\text{ A}, T_J = 150^\circ\text{C}$		32		
		$V_{GS} = 18\text{V}, I_D = 40\text{ A}, T_J = 175^\circ\text{C}$		34		
		$V_{DS} = 20\text{V}, I_D = 40\text{ A}, T_J = 150^\circ\text{C}$		20		
Transconductance	$g_{fs}$	$V_{DS} = 20\text{V}, I_D = 40\text{ A}, T_J = 175^\circ\text{C}$		20		S
		$V_{DS} = 20\text{V}, I_D = 40\text{ A}, T_J = 175^\circ\text{C}$		20		
		$V_{DS} = 20\text{V}, I_D = 40\text{ A}, T_J = 175^\circ\text{C}$		20		
Input capacitance	$C_{iss}$			3480		pF
Output capacitance	$C_{oss}$			295		
Reverse transfer capacitance	$C_{rss}$			13		
$C_{oss}$ Stored Energy	$E_{oss}$			28		$\mu\text{J}$
Total gate charge	$Q_g$	$V_{DS} = 400\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$		163		nC
Gate-source charge	$Q_{gs}$			47		
Gate-drain charge	$Q_{gd}$			65		
Internal gate input resistance	$R_{g(\text{int})}$	$f = 1\text{MHz}, I_D = 0\text{A}$		2.0		$\Omega$
Turn-On Switching Energy	$E_{ON}$	$V_{DS} = 400\text{ V}, V_{GS} = -4\text{V} / 18\text{V}$ $I_D = 40\text{ A}$		44		$\mu\text{J}$
Turn-Off Switching Energy	$E_{OFF}$			46		
Turn-On Delay Time	$t_{d(on)}$			12		
Rise Time	$t_r$			14		
Turn-Off Delay Time	$t_{d(off)}$			31		
Fall Time	$t_f$			7		
Avalanche Capability	$E_{AS}$	$V_{DD} = 100\text{V}, V_{GS}=18\text{V}, L=1\text{mH}$		312		$\text{mJ}$
Avalanche Capability	$I_{AV}$			25		A

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**LGE3M30065Q**  
Silicon CarbidePower MOSFET



**Reverse Diode Characteristics** ( $T_C=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Diode Forward Voltage	$V_{SD}$	$V_{GS} = -4V, I_{SD} = 20A,$		3.9		V
		$V_{GS} = -4V, I_{SD} = 20A, T_J = 150^\circ\text{C}$		3.5		
		$V_{GS} = -4V, I_{SD} = 20A, T_J = 175^\circ\text{C}$		3.4		
Continuous Diode Forward Current	$I_S$	$V_{GS} = -5V$		62		A
Reverse Recovery time	$t_{rr}$	$V_{GS} = -4V, I_{SD} = 40A,$ $V_R = 400V, \text{dif/dt} = 3300 A/\mu\text{s}$		23		ns
Reverse Recovery Charge	$Q_{rr}$			430		nC
Peak Reverse Recovery Current	$I_{rrm}$			32		A

**Thermal Characteristics**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Thermal Resistance (per device)	$R_{th(j-c)}$	junction-case		0.37	0.46	$^\circ\text{C/W}$

Caution: This device is sensitive to electrostatic discharge .Users should follow ESD handing procedures.

## Typical Performance

**LGE3M30065Q**

Silicon CarbidePower MOSFET

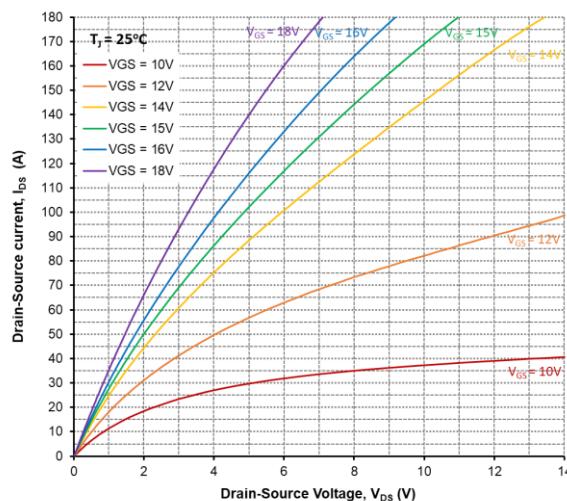


Figure 1. Output Characteristics,  $T_J = 25^\circ\text{C}$

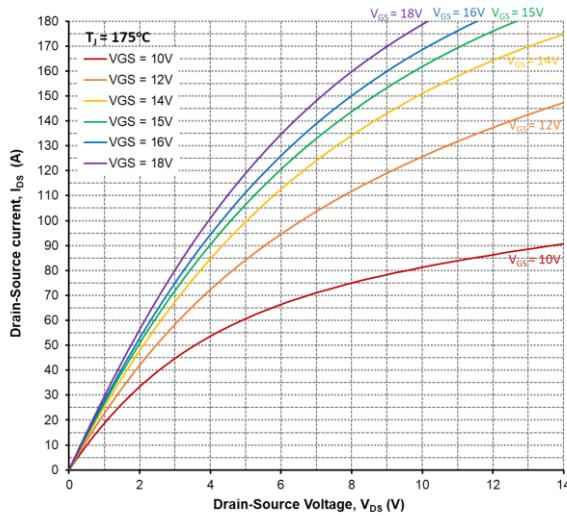


Figure 2. Output Characteristics,  $T_J = 175^\circ\text{C}$

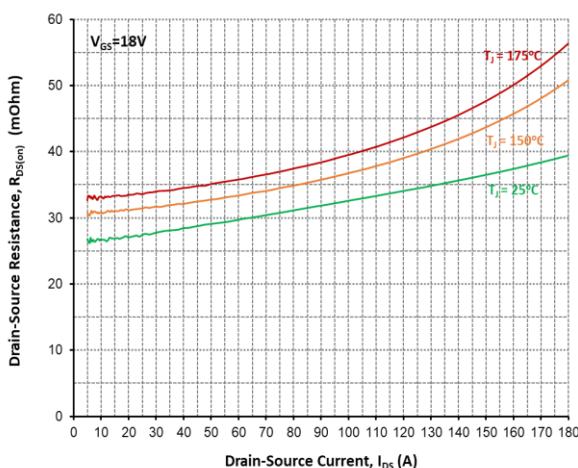


Figure 3. On-Resistance vs. Drain Current  
For Various Temperatures

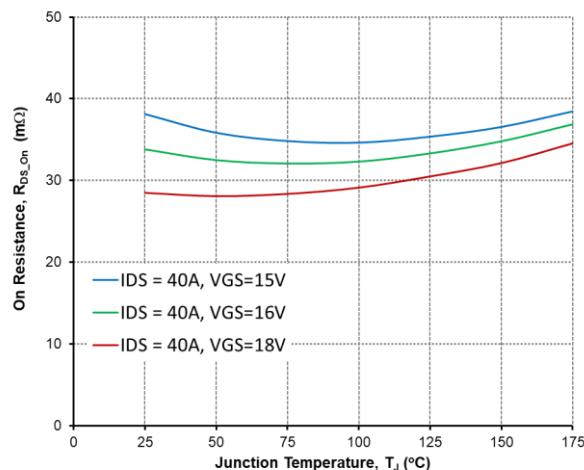


Figure 4. On-Resistance vs. Temperature

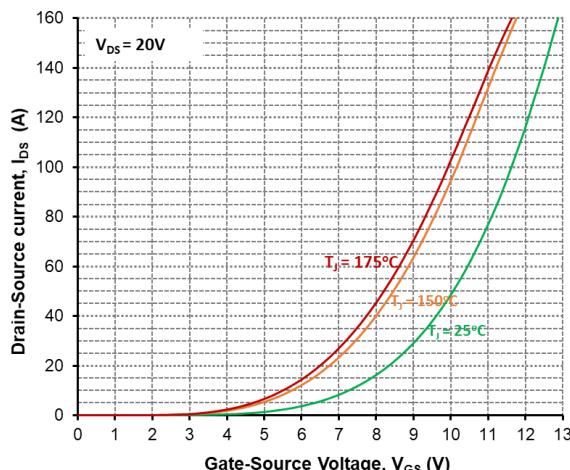


Figure 5. Transfer Characteristic For Various Junction  
Temperatures

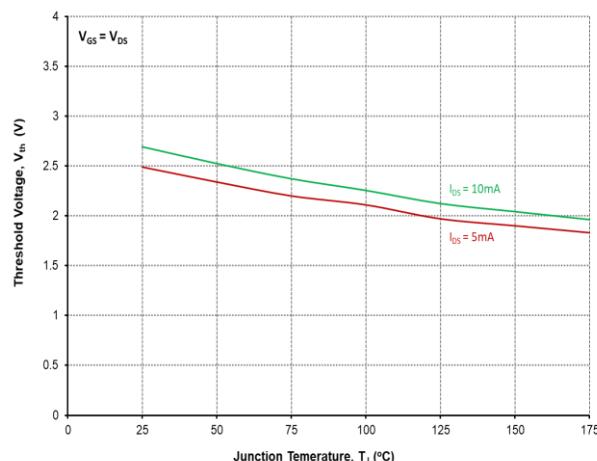


Figure 6. Threshold Voltage vs. Temperature

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handing procedures.

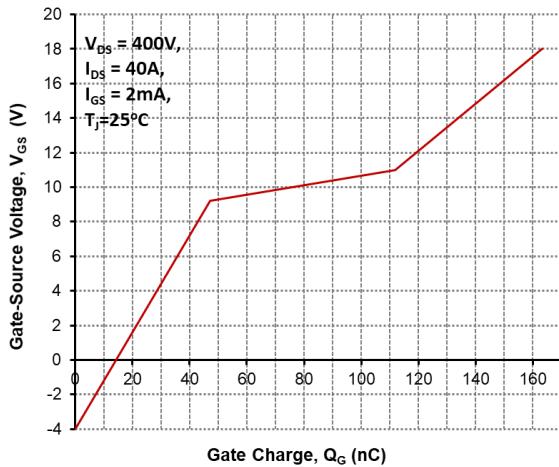


Figure 7. Gate Charge Characteristics

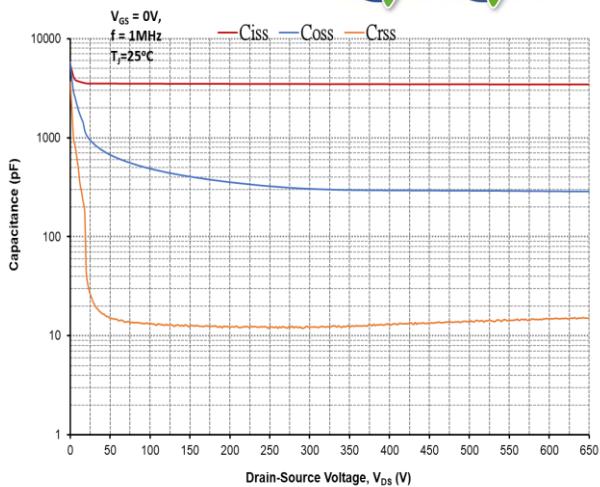


Figure 8. Capacitances vs. Drain-Source Voltage (0-650V)

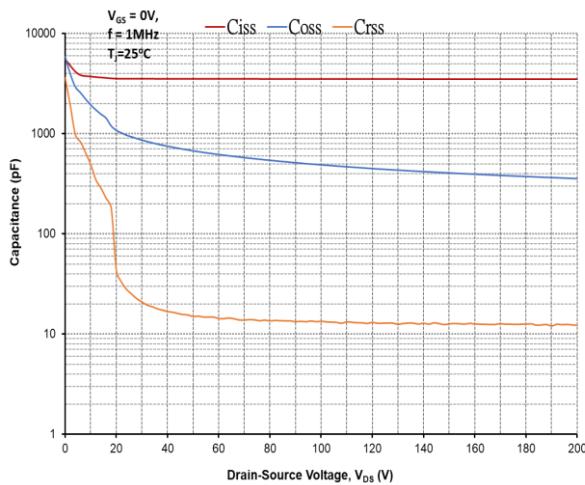


Figure 9. Capacitances vs. Drain-Source Voltage (0-200V)

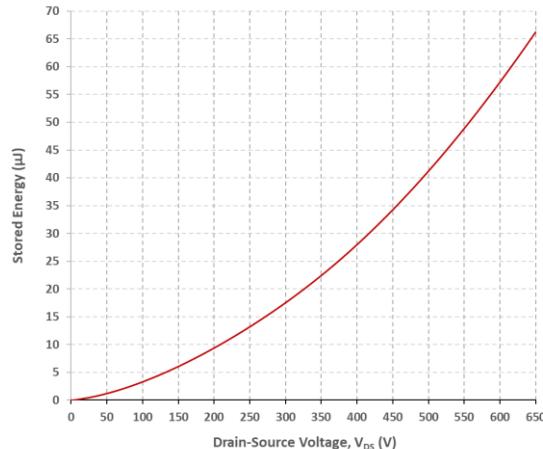


Figure 10. Output Capacitor Stored Energy

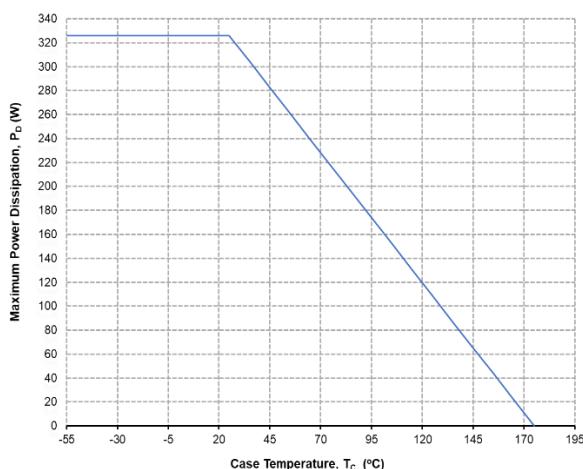


Figure 11. Maximum Power Dissipation Derating vs. Case Temperature

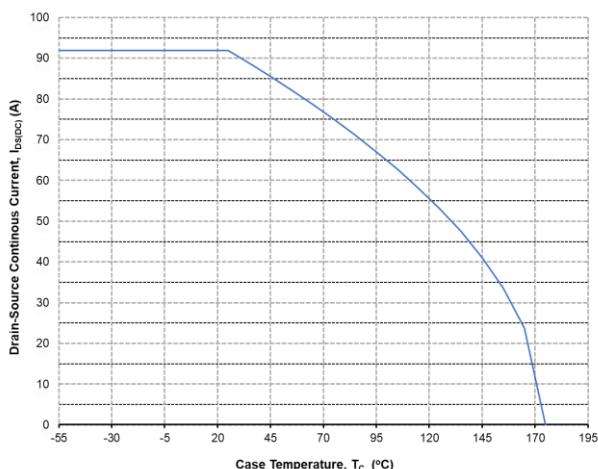


Figure 12. Continuous Drain Current Derating vs. Case Temperature

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handing procedures.

## Typical Performance

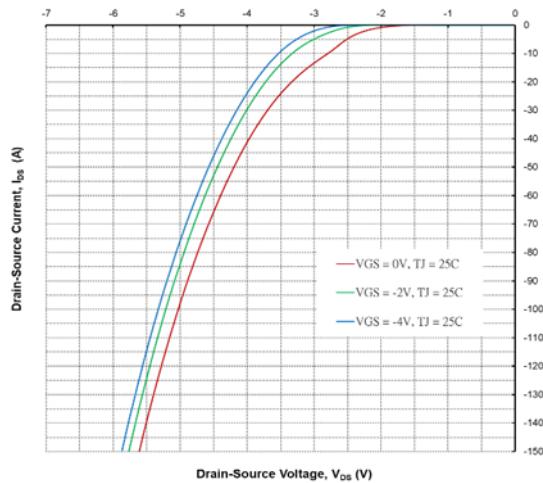


Figure 13. Body Diode Characteristics @  $25^\circ\text{C}$

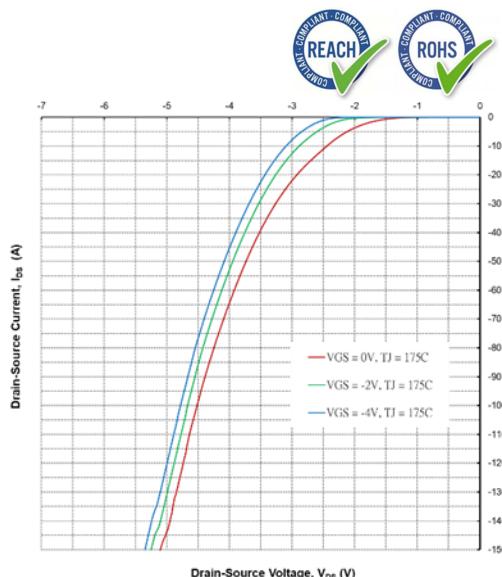


Figure 14. Body Diode Characteristics @  $175^\circ\text{C}$

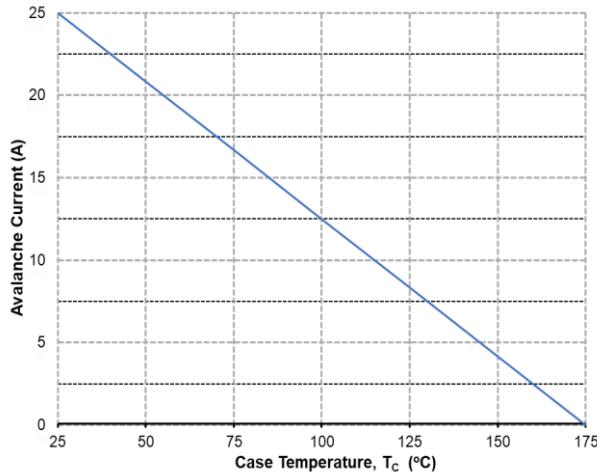


Figure 15. Single Avalanche vs. Temperature

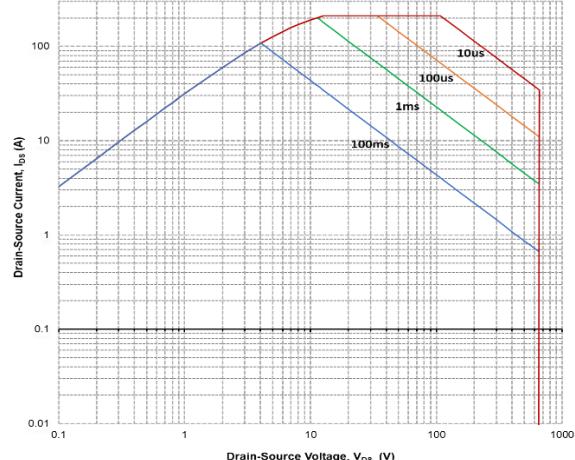
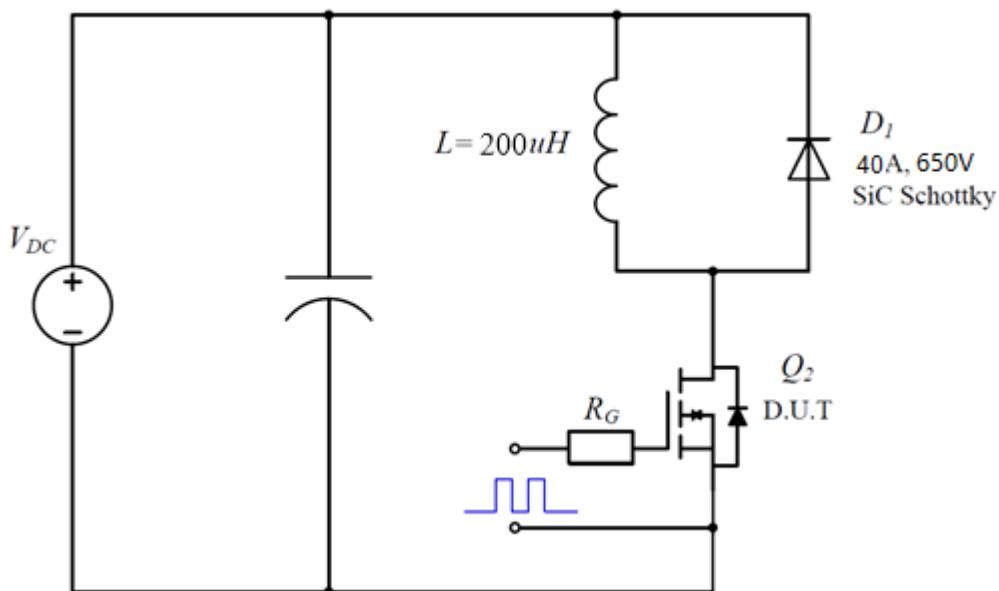
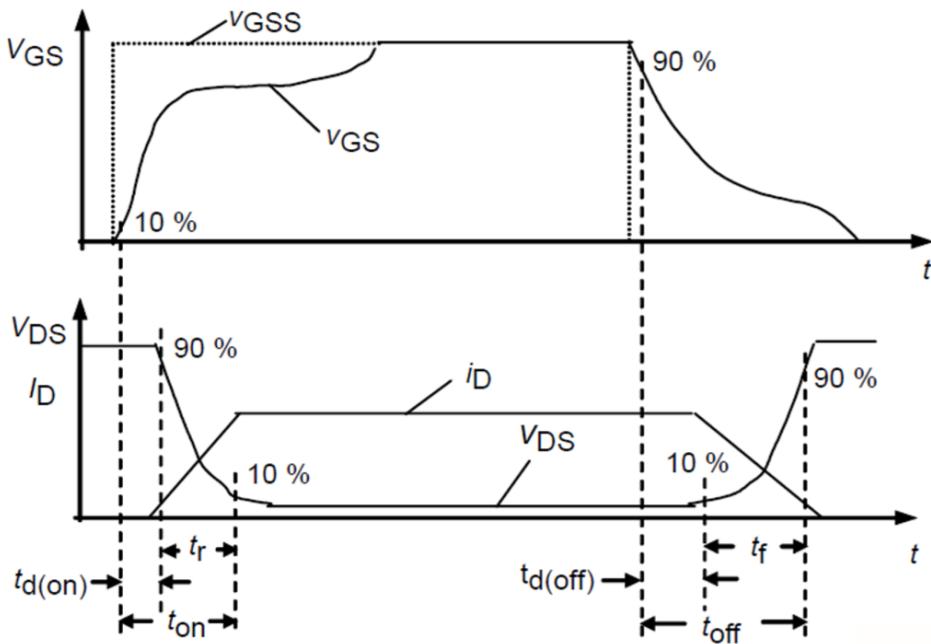


Figure 16. Safe Operating Area

Caution: This device is sensitive to electrostatic discharge .Users should follow ESD handing procedures.

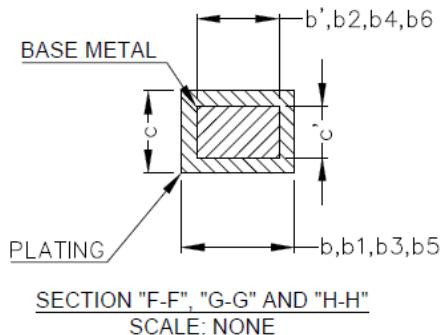
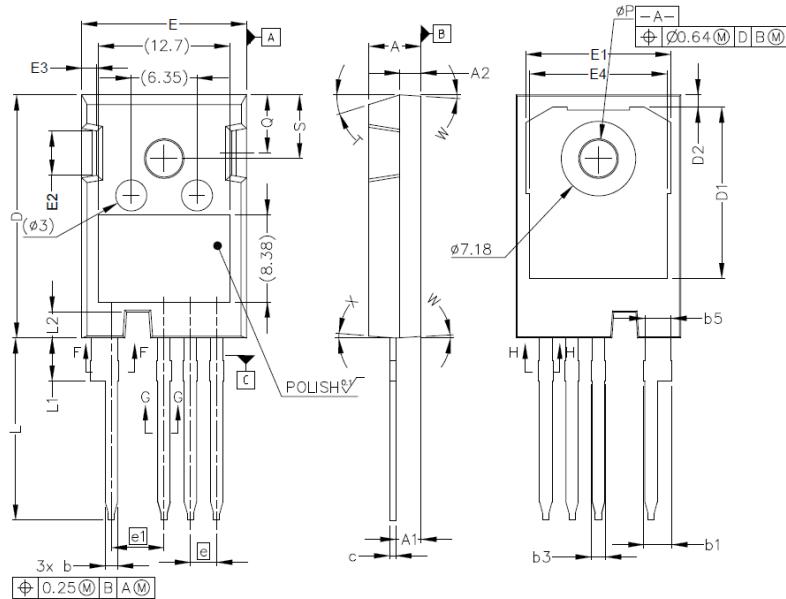


## Switching Times Definition and Test Circuit



Caution: This device is sensitive to electrostatic discharge .Users should follow ESD handing procedures.

(TO-247-4 Package)



SYMBOL	MILLIMETERS	
	MIN	MAX
A	4.83	5.21
A1	2.29	2.54
A2	1.91	2.16
b'	1.07	1.28
b	1.07	1.33
b1	2.39	2.94
b2	2.39	2.84
b3	1.07	1.60
b4	1.07	1.50
b5	2.39	2.69
b6	2.39	2.64
c'	0.55	0.65
c	0.55	0.68
D	23.30	23.60
D1	16.25	17.65
D2	0.95	1.25
E	15.75	16.13
E1	13.10	14.15
E2	3.68	5.10
E3	1.00	1.90
E4	12.38	13.43
e	2.54	BSC
e1	5.08	BSC
N	4	
L	17.31	17.82
L1	3.97	4.37
L2	2.35	2.65
øP	3.51	3.65
Q	5.49	6.00
S	6.04	6.30
T	17.5°	REF.
W	3.5 °	REF.
X	4 °	REF.

**NOTE :**

- ALL METAL SURFACES: TIN PLATED,EXCEPT AREA OF CUT
- DIMENSIONING & TOLERANCING CONFIRM TO ASME Y14.5M-1994.
- ALL DIMENSIONS ARE IN MILLIMETERS.  
ANGLES ARE IN DEGREES.

Packge	Packing	Box Size L×W×H(mm)	Quatity(pcs/box)	Carton Size L×W×H(mm)	Quatity(pcs/carton)
TO-247	30pcs/Tube	570×155×50	450	580×340×125	1800

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